## Joint ICTP-IAEA Advanced Workshop on Multi-Scale Modelling for Characterization and Basic Understanding of Radiation Damage Mechanisms in Materials | (smr 2137)

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## New radiation based microscopes

Tuesday, 20 April 2010 16:30 (1:00)

Content

Summary

Presenter(s): C. TUNIZ (ICTP, Trieste, Italy)

Session Classification: New radiation based microscopes